



Vincotech

flowNPC 2

600V/200A

Features

- Neutral-point-Clamped inverter
- High power flow2 housing
- High Speed IGBT3 in Buck
- Low Inductance Layout

Target Applications

- UPS
- Solar inverters

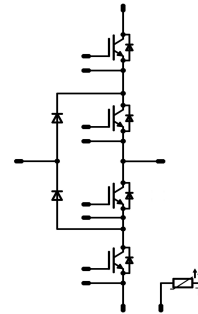
Types

- F206NIA200SG

flow2 housing



Schematic



Maximum Ratings

T_j=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
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Buck IGBT

Collector-emitter break down voltage	V _{CE}		600	V
DC collector current	I _C	T _j =T _{jmax} T _n =80°C T _c =80°C	143 188	A
Repetitive peak collector current	I _{Cpulse}	t _p limited by T _{jmax}	800	A
Power dissipation	P _{tot}	T _j =T _{jmax} T _n =80°C T _c =80°C	286 433	W
Gate-emitter peak voltage	V _{GE}		±20	V
Short circuit ratings	t _{SC} V _{CC}	T _j ≤150°C V _{GE} =15V	5 400	μs V
Maximum Junction Temperature	T _{jmax}		175	°C

Buck FWD

Peak Repetitive Reverse Voltage	V _{RRM}	T _j =25°C	600	V
DC forward current	I _F	T _j =T _{jmax} T _n =80°C T _c =80°C	96 129	A
Repetitive peak forward current	I _{FRM}	t _p limited by T _{jmax} T _c =100°C	240	A
Power dissipation	P _{tot}	T _j =T _{jmax} T _n =80°C T _c =80°C	141 175	W
Maximum Junction Temperature	T _{jmax}		175	°C



Maximum Ratings

T_j=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
Boost IGBT				
Collector-emitter break down voltage	V _{CE}		600	V
DC collector current	I _C	T _j =T _{jmax} T _h =80°C T _c =80°C	151 198	A
Repetitive peak collector current	I _{Cpuls}	t _p limited by T _{jmax}	600	A
Power dissipation	P _{tot}	T _j =T _{jmax} T _h =80°C T _c =80°C	245 372	W
Gate-emitter peak voltage	V _{GE}		±20	V
Short circuit ratings	t _{SC}	T _j ≤150°C	6	μs
	V _{CC}	V _{GE} =15V	360	V
Maximum Junction Temperature	T _{jmax}		175	°C

Boost Inverse Diode

Peak Repetitive Reverse Voltage	V _{RRM}	T _c =25°C	1200	V
DC forward current	I _F	T _j =T _{jmax} T _h =80°C T _c =80°C	134 178	A
Repetitive peak forward current	I _{FRM}	t _p limited by T _{jmax}	600	A
Power dissipation per Diode	P _{tot}	T _j =T _{jmax} T _h =80°C T _c =80°C	195 295	W
Maximum Junction Temperature	T _{jmax}		175	°C

Boost FWD

Peak Repetitive Reverse Voltage	V _{RRM}	T _j =25°C	600	V
DC forward current	I _F	T _j =T _{jmax} T _h =80°C T _c =80°C	134 178	A
Repetitive peak forward current	I _{FRM}	t _p limited by T _{jmax}	600	A
Power dissipation	P _{tot}	T _j =T _{jmax} T _h =80°C T _c =80°C	195 295	W
Maximum Junction Temperature	T _{jmax}		175	°C

Thermal Properties

Storage temperature	T _{stg}		-40...+125	°C
Operation temperature under switching condition	T _{op}		-40...+(T _{jmax} - 25)	°C

Insulation Properties

Insulation voltage	V _{is}	t=2s DC voltage	4000	V
Creepage distance			min 12,7	mm
Clearance			min 12,7	mm

Characteristic Values

Parameter	Symbol	Conditions					Value			Unit
		$V_{GE}[V]$ or $V_{GS}[V]$	$V_r[V]$ or $V_{CE}[V]$ or $V_{DS}[V]$	$I_c[A]$ or $I_F[A]$ or $I_b[A]$	T_j	Min	Typ	Max		

Buck IGBT

Gate emitter threshold voltage	$V_{GE(th)}$	VCE=VGE			0,0008	$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$	4,1	5,1	5,7	V
Collector-emitter saturation voltage	$V_{CE(sat)}$		15		50	$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$		1,88 2,17	2,3	V
Collector-emitter cut-off current incl. Diode	I_{CES}		0	600		$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$			0,7	μA
Gate-emitter leakage current	I_{GES}		20	0		$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$			960	μA
Integrated Gate resistor	R_{gint}							none		Ω
Turn-on delay time	$t_{d(on)}$	Rgoff=4 Ω Rgon=4 Ω	± 15	350	200	$T_j=25^\circ\text{C}$		200		ns
Rise time	t_r					$T_j=150^\circ\text{C}$		200		
Turn-off delay time	$t_{d(off)}$					$T_j=25^\circ\text{C}$		43		
Fall time	t_f					$T_j=150^\circ\text{C}$		46		
Turn-on energy loss per pulse	E_{on}					$T_j=25^\circ\text{C}$		248		
Turn-off energy loss per pulse	E_{off}					$T_j=150^\circ\text{C}$		270		
Input capacitance	C_{ies}					$T_j=25^\circ\text{C}$		11840		pF
Output capacitance	C_{oss}	f=1MHz	0	25		$T_j=25^\circ\text{C}$		464		
Reverse transfer capacitance	C_{riss}							384		
Gate charge	Q_{Gate}		15	700	200	$T_j=25^\circ\text{C}$		2000		nC
Thermal resistance chip to heatsink	R_{thJH}	Thermal grease thickness $\leq 50\mu\text{m}$						0,33		K/W
Thermal resistance chip to case	R_{thJC}	$\lambda = 1 \text{ W/mK}$						0,22		

Buck FWD

Diode forward voltage	V_F				120	$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$		2,59 2,23		V
Peak reverse recovery current	I_{RRM}	Rgoff=4 Ω	0	350	200	$T_j=25^\circ\text{C}$		99		A
Reverse recovery time	t_{rr}					$T_j=150^\circ\text{C}$		154		
Reverse recovered charge	Q_{rr}					$T_j=25^\circ\text{C}$		42		
Peak rate of fall of recovery current	$di(rec)_{max}/dt$					$T_j=150^\circ\text{C}$		111		
Reverse recovered energy	E_{rec}					$T_j=25^\circ\text{C}$		2,6		
						$T_j=150^\circ\text{C}$		7,3		
Thermal resistance chip to heatsink	R_{thJH}	Thermal grease thickness $\leq 50\mu\text{m}$						0,67		K/W
Thermal resistance chip to case	R_{thJC}	$\lambda = 1 \text{ W/mK}$						0,44		

Characteristic Values

Parameter	Symbol	Conditions					Value			Unit
		$V_{GE}[V]$ or $V_{GS}[V]$	$V_r[V]$ or $V_{CE}[V]$ or $V_{DS}[V]$	$I_c[A]$ or $I_F[A]$ or $I_b[A]$	T_j	Min	Typ	Max		

Boost IGBT

Gate emitter threshold voltage	$V_{GE(th)}$	$V_{CE}=V_{GE}$			0,0032	$T_j=25^\circ C$ $T_j=125^\circ C$	5	5,8	6,5	V
Collector-emitter saturation voltage	$V_{CE(sat)}$		15		200	$T_j=25^\circ C$ $T_j=150^\circ C$	1,05	1,53 1,72	1,85	V
Collector-emitter cut-off incl diode	I_{CES}		0	600		$T_j=25^\circ C$ $T_j=150^\circ C$			0,96	mA
Gate-emitter leakage current	I_{GES}		20	0		$T_j=25^\circ C$ $T_j=150^\circ C$			700	nA
Integrated Gate resistor	R_{gint}							1		Ω
Turn-on delay time	$t_{d(on)}$	$R_{goff}=4 \Omega$ $R_{gon}=4 \Omega$	± 15	350	200	$T_j=25^\circ C$		233		ns
Rise time	t_r					$T_j=150^\circ C$		238		
Turn-off delay time	$t_{d(off)}$					$T_j=25^\circ C$		43		
Fall time	t_f					$T_j=150^\circ C$		47		
Turn-on energy loss per pulse	E_{on}					$T_j=25^\circ C$		309		
Turn-off energy loss per pulse	E_{off}	$T_j=150^\circ C$		334						
Input capacitance	C_{ies}					$T_j=25^\circ C$		12320		pF
Output capacitance	C_{oss}	$f=1MHz$	0	25		$T_j=25^\circ C$		768		
Reverse transfer capacitance	C_{rss}							366		
Gate charge	Q_{Gate}		15	480	200	$T_j=25^\circ C$		2100		nC
Thermal resistance chip to heatsink	R_{thJH}	Thermal grease thickness $\leq 50\mu m$						0,39		K/W
Thermal resistance chip to case	R_{thJC}	$\lambda = 1 W/mK$						0,26		

Boost Inverse Diode

Diode forward voltage	V_F				20	$T_j=25^\circ C$ $T_j=125^\circ C$		1,67 1,72		V
Thermal resistance chip to heatsink	R_{thJH}	Thermal grease thickness $\leq 50\mu m$						0,49		K/W
Thermal resistance chip to case	R_{thJC}	$\lambda = 1 W/mK$						0,32		

Boost FWD

Diode forward voltage	V_F				200	$T_j=25^\circ C$ $T_j=150^\circ C$	1,5	1,66 1,72	3,3	V
Reverse leakage current	I_r			600		$T_j=25^\circ C$ $T_j=150^\circ C$			600	μA
Peak reverse recovery current	I_{RRM}	$R_{goff}=4 \Omega$	± 15	350	200	$T_j=25^\circ C$		131		A
Reverse recovery time	t_{rr}					$T_j=150^\circ C$		168		
Reverse recovered charge	Q_{rr}					$T_j=25^\circ C$		136		
Peak rate of fall of recovery current	$di(rec)max/dt$					$T_j=150^\circ C$		285		
Reverse recovery energy	E_{rec}					$T_j=25^\circ C$		9,0		
Thermal resistance chip to heatsink	R_{thJH}	Thermal grease thickness $\leq 50\mu m$						0,49		K/W
Thermal resistance chip to case	R_{thJC}	$\lambda = 1 W/mK$						0,32		

Thermistor

Rated resistance	R					$T=25^\circ C$		22000		Ω
Deviation of R100	$\Delta R/R$	R100=1486 Ω				$T=100^\circ C$	-5		5	%
Power dissipation	P					$T=25^\circ C$		200		mW
Power dissipation constant						$T=25^\circ C$		2		mW/K
B-value	B(25/50)	Tol. $\pm 3\%$				$T=25^\circ C$		3950		K
B-value	B(25/100)	Tol. $\pm 3\%$				$T=25^\circ C$		3996		K
Vincotech NTC Reference									B	

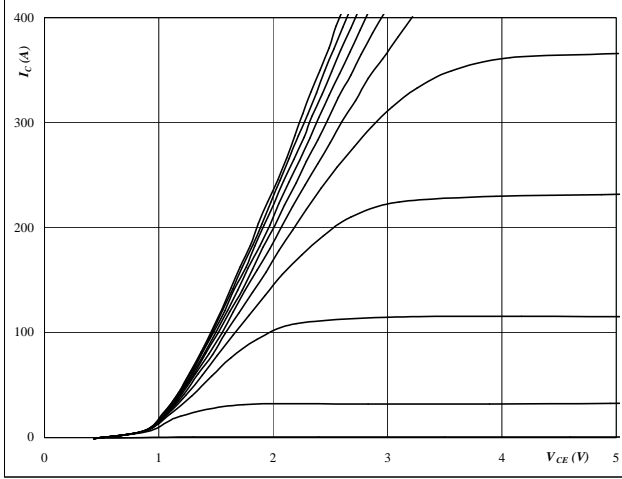


Buck

Figure 1 IGBT

Typical output characteristics

$I_C = f(V_{CE})$

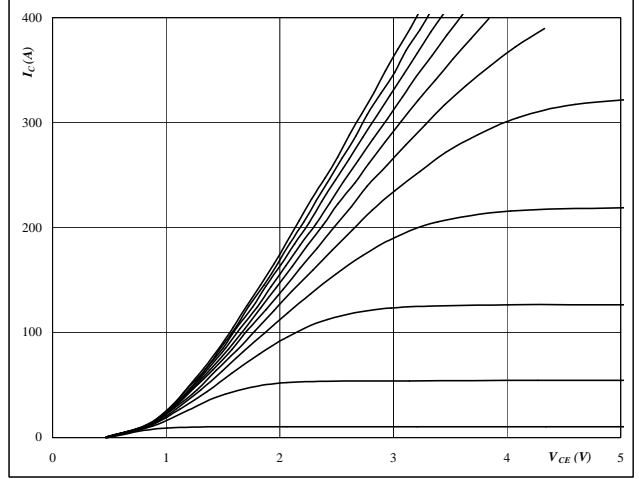


At
 $t_p = 250 \mu s$
 $T_j = 25 \text{ }^\circ C$
 V_{GE} from 6 V to 16 V in steps of 1 V

Figure 2 IGBT

Typical output characteristics

$I_C = f(V_{CE})$

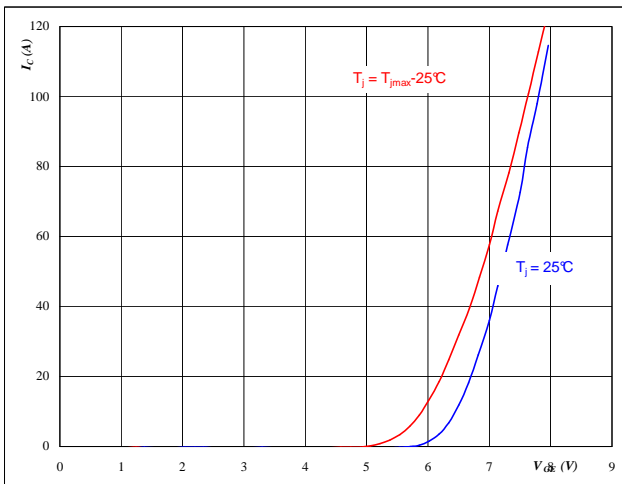


At
 $t_p = 250 \mu s$
 $T_j = 125 \text{ }^\circ C$
 V_{GE} from 6 V to 16 V in steps of 1 V

Figure 3 IGBT

Typical transfer characteristics

$I_C = f(V_{GE})$

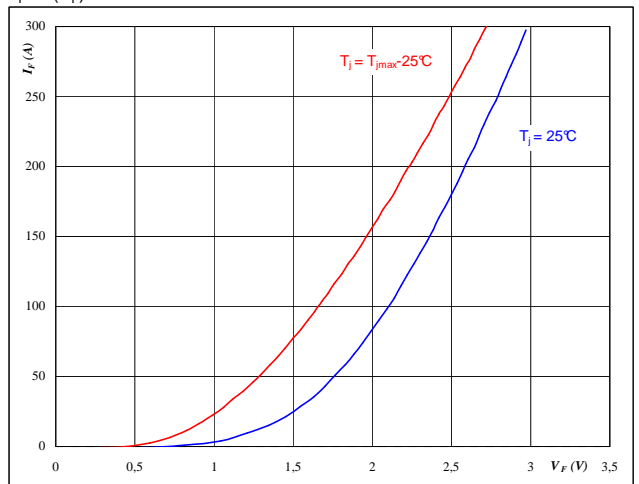


At
 $t_p = 250 \mu s$
 $V_{CE} = 10 V$

Figure 4 Diode

Typical diode forward current as a function of forward voltage

$I_F = f(V_F)$



At
 $t_p = 250 \mu s$

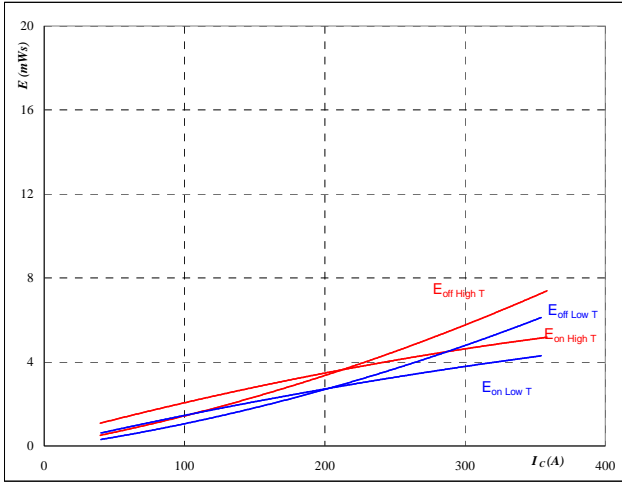


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Figure 5 IGBT

Typical switching energy losses
as a function of collector current

$E = f(I_c)$



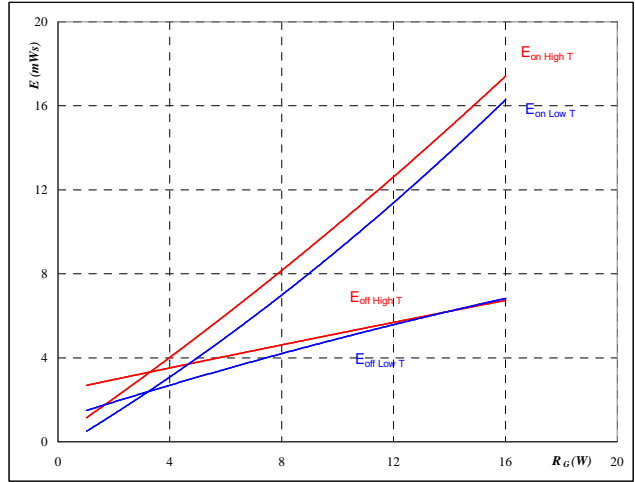
With an inductive load at

- $T_j = 25/125 \text{ } ^\circ\text{C}$
- $V_{CE} = 350 \text{ V}$
- $V_{GE} = \pm 15 \text{ V}$
- $R_{gon} = 4 \text{ } \Omega$
- $R_{goff} = 4 \text{ } \Omega$

Figure 6 IGBT

Typical switching energy losses
as a function of gate resistor

$E = f(R_G)$



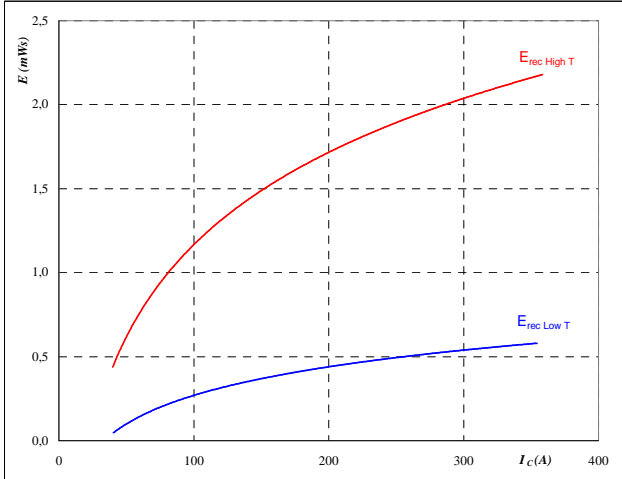
With an inductive load at

- $T_j = 25/125 \text{ } ^\circ\text{C}$
- $V_{CE} = 350 \text{ V}$
- $V_{GE} = \pm 15 \text{ V}$
- $I_c = 200 \text{ A}$

Figure 7 Diode

Typical reverse recovery energy loss
as a function of collector current

$E_{rec} = f(I_c)$



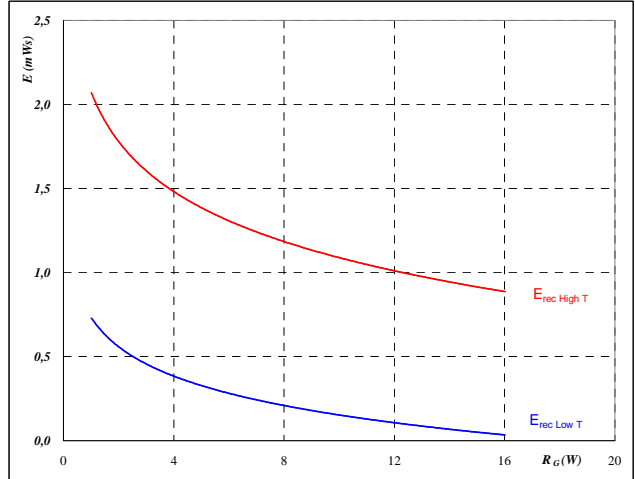
With an inductive load at

- $T_j = 25/125 \text{ } ^\circ\text{C}$
- $V_{CE} = 350 \text{ V}$
- $V_{GE} = \pm 15 \text{ V}$
- $R_{gon} = 4 \text{ } \Omega$

Figure 8 Diode

Typical reverse recovery energy loss
as a function of gate resistor

$E_{rec} = f(R_G)$



With an inductive load at

- $T_j = 25/125 \text{ } ^\circ\text{C}$
- $V_{CE} = 350 \text{ V}$
- $V_{GE} = \pm 15 \text{ V}$
- $I_c = 200 \text{ A}$

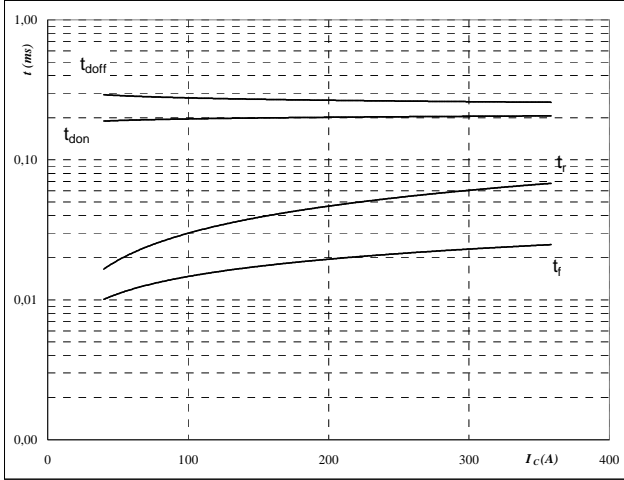


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Figure 9 IGBT

Typical switching times as a function of collector current

$t = f(I_C)$



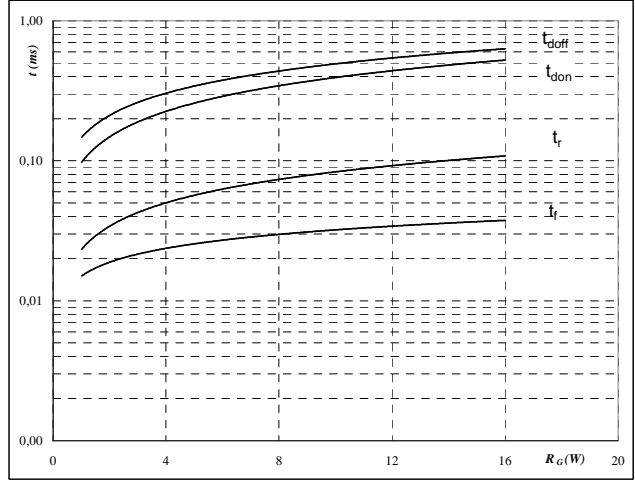
With an inductive load at

$T_J =$	125	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$R_{gon} =$	4	Ω
$R_{goff} =$	4	Ω

Figure 10 IGBT

Typical switching times as a function of gate resistor

$t = f(R_G)$



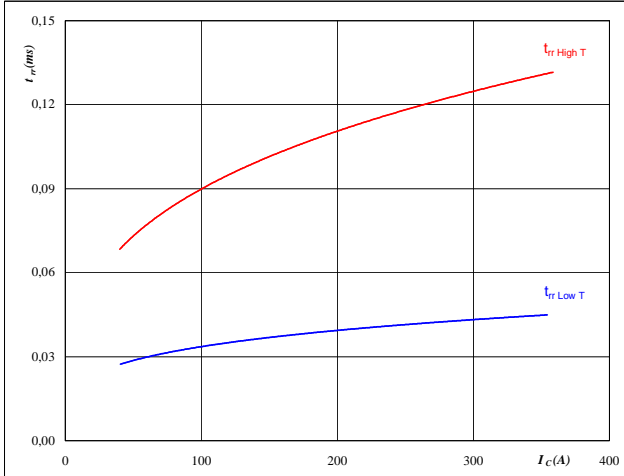
With an inductive load at

$T_J =$	125	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$I_C =$	200	A

Figure 11 Diode

Typical reverse recovery time as a function of collector current

$t_{rr} = f(I_C)$



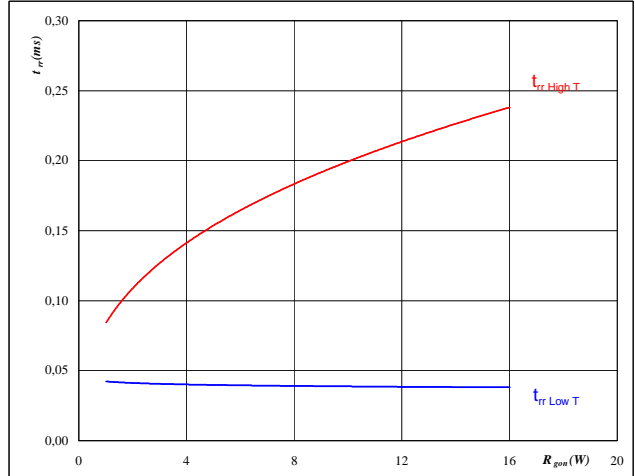
At

$T_J =$	25/125	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$R_{gon} =$	4	Ω

Figure 12 Diode

Typical reverse recovery time as a function of IGBT turn on gate resistor

$t_{rr} = f(R_{gon})$



At

$T_J =$	25/125	°C
$V_R =$	350	V
$I_F =$	200	A
$V_{GE} =$	±15	V

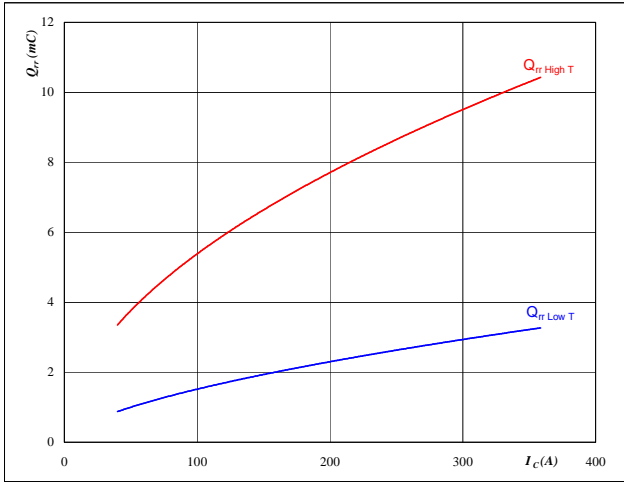


Buck

Figure 13 Diode

Typical reverse recovery charge as a function of collector current

$Q_{rr} = f(I_c)$

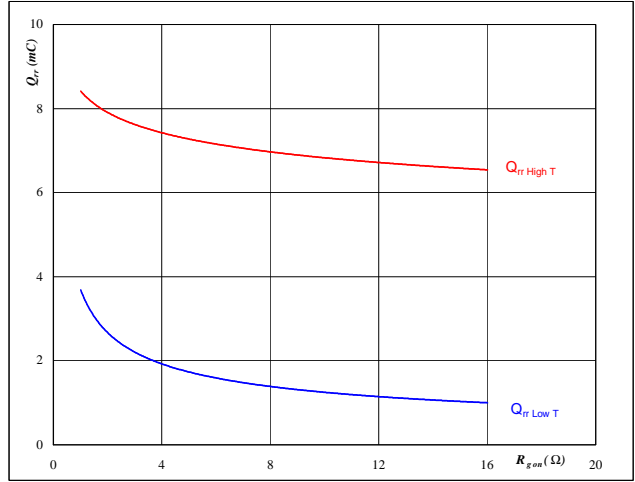


At
 $T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = \pm 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$

Figure 14 Diode

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$Q_{rr} = f(R_{gon})$

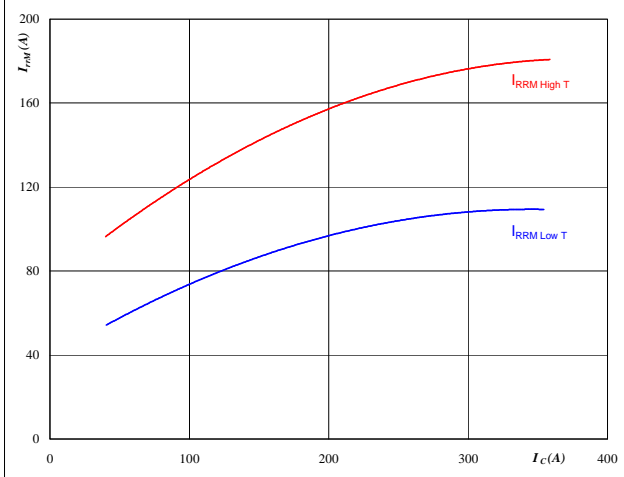


At
 $T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_R = 350 \text{ V}$
 $I_F = 200 \text{ A}$
 $V_{GE} = \pm 15 \text{ V}$

Figure 15 Diode

Typical reverse recovery current as a function of collector current

$I_{RRM} = f(I_c)$

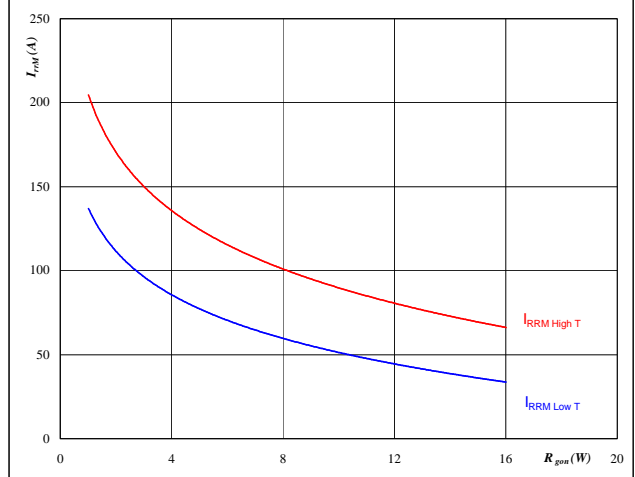


At
 $T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = \pm 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$

Figure 16 Diode

Typical reverse recovery current as a function of IGBT turn on gate resistor

$I_{RRM} = f(R_{gon})$



At
 $T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_R = 350 \text{ V}$
 $I_F = 200 \text{ A}$
 $V_{GE} = \pm 15 \text{ V}$

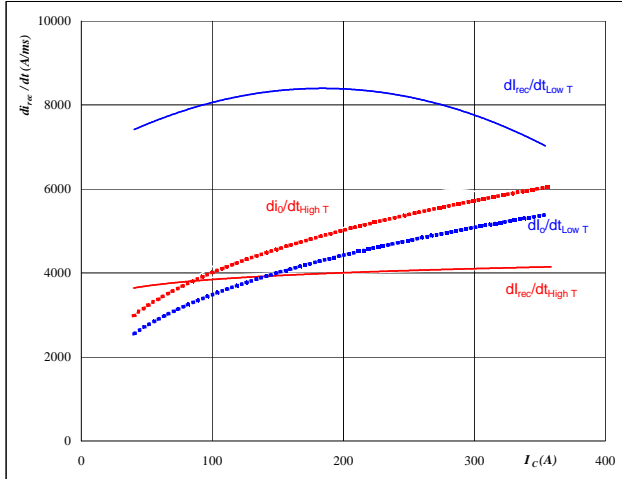


Buck

Figure 17 Diode

Typical rate of fall of forward and reverse recovery current as a function of collector current

$di_o/dt, di_{rec}/dt = f(I_c)$

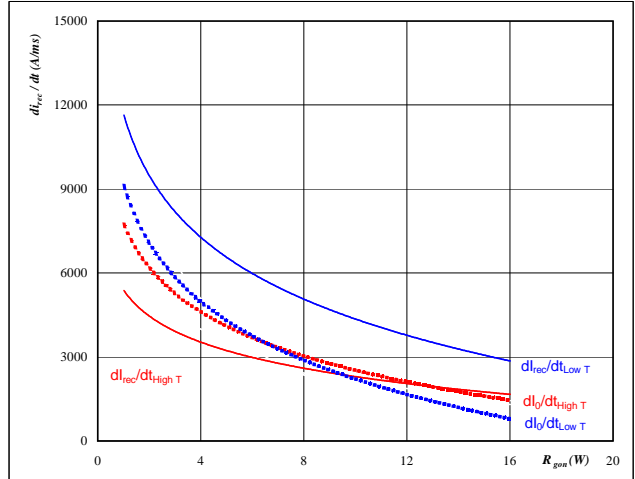


At
 $T_j = 25/125$ °C
 $V_{CE} = 350$ V
 $V_{GE} = \pm 15$ V
 $R_{gon} = 4$ Ω

Figure 18 Diode

Typical rate of fall of forward and reverse recovery current as a function of IGBT turn on gate resistor

$di_o/dt, di_{rec}/dt = f(R_{gon})$

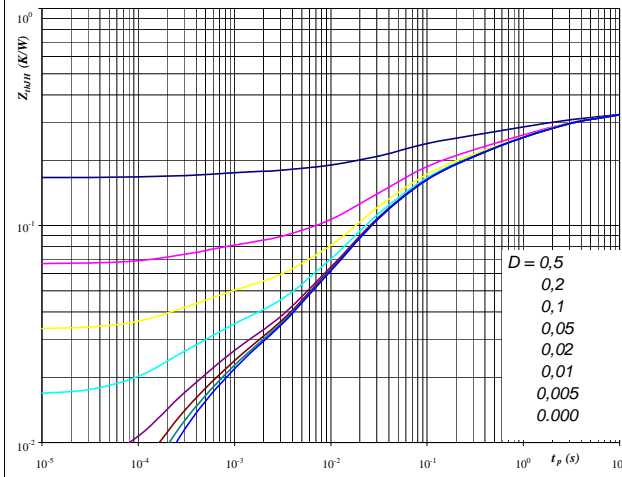


At
 $T_j = 25/125$ °C
 $V_R = 350$ V
 $I_F = 200$ A
 $V_{GE} = \pm 15$ V

Figure 19 IGBT

IGBT transient thermal impedance as a function of pulse width

$Z_{thJH} = f(t_p)$



At
 $D = t_p / T$
 $R_{thJH} = 0,33$ K/W

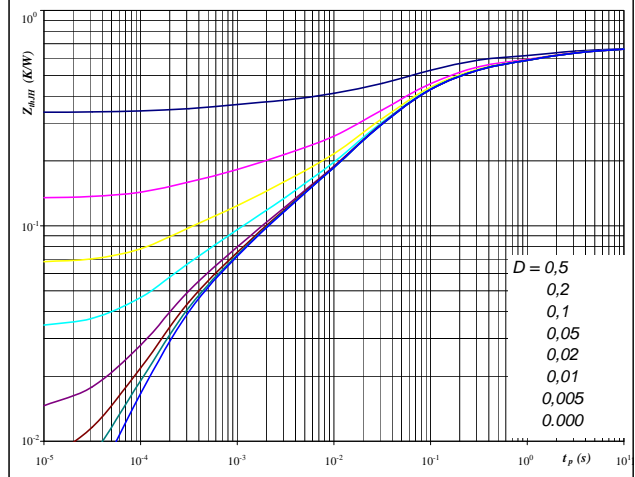
IGBT thermal model values

R (C/W)	Tau (s)
0,05	5,4E+00
0,08	1,2E+00
0,07	1,9E-01
0,10	3,1E-02
0,02	4,2E-03
0,02	3,4E-04

Figure 20 Diode

Diode transient thermal impedance as a function of pulse width

$Z_{thJH} = f(t_p)$



At
 $D = t_p / T$
 $R_{thJH} = 0,67$ K/W

Diode thermal model values

R (C/W)	Tau (s)
0,05	6,2E+00
0,11	1,1E+00
0,23	1,1E-01
0,18	2,4E-02
0,06	2,3E-03
0,04	2,6E-04

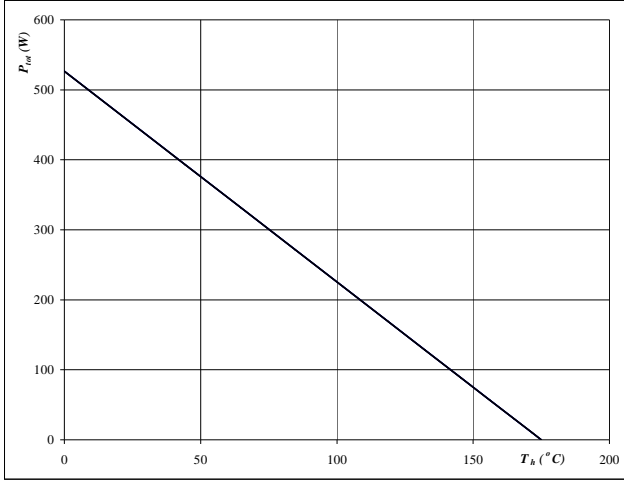


Buck

Figure 21 IGBT

Power dissipation as a function of heatsink temperature

$P_{tot} = f(T_h)$

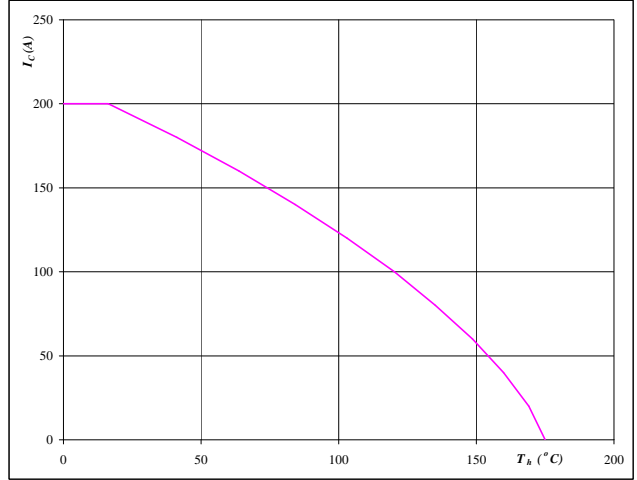


At
T_j = 175 °C

Figure 22 IGBT

Collector current as a function of heatsink temperature

$I_C = f(T_h)$

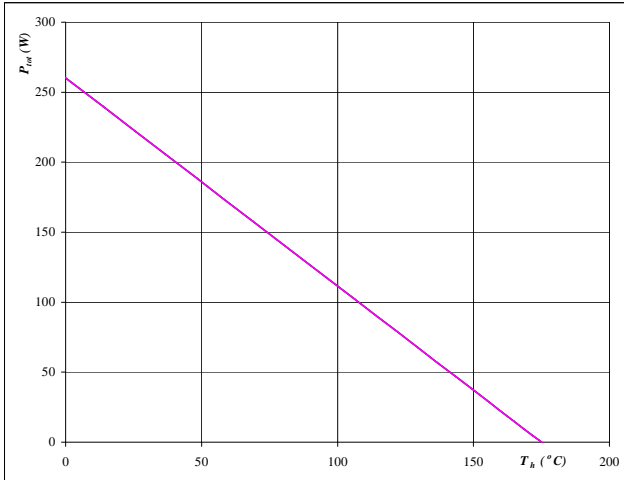


At
T_j = 175 °C
V_{GE} = 15 V

Figure 23 Diode

Power dissipation as a function of heatsink temperature

$P_{tot} = f(T_h)$

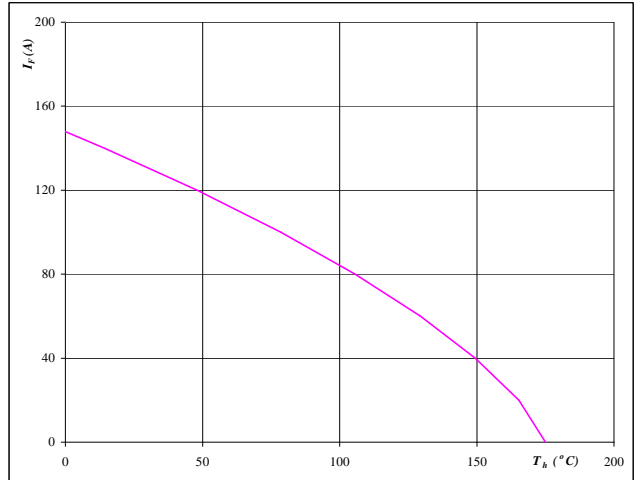


At
T_j = 175 °C

Figure 24 Diode

Forward current as a function of heatsink temperature

$I_F = f(T_h)$



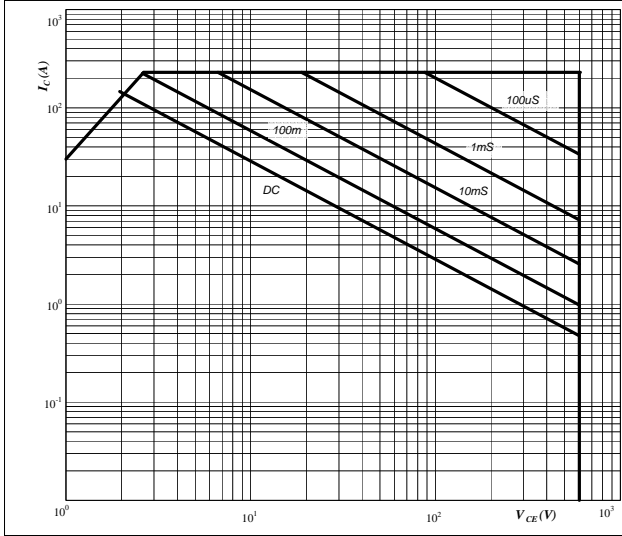
At
T_j = 175 °C



Buck

Figure 25 IGBT

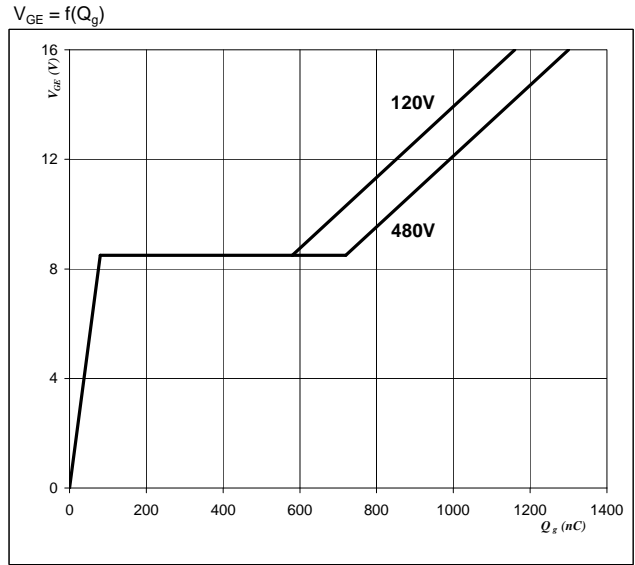
Safe operating area as a function
of collector-emitter voltage
 $I_C = f(V_{CE})$



At
 D = single pulse
 Th = 80 °C
 $V_{GE} = \pm 15$ V
 $T_j = T_{jmax}$ °C

Figure 26 IGBT

Gate voltage vs Gate charge



At
 $I_C = 200$ A

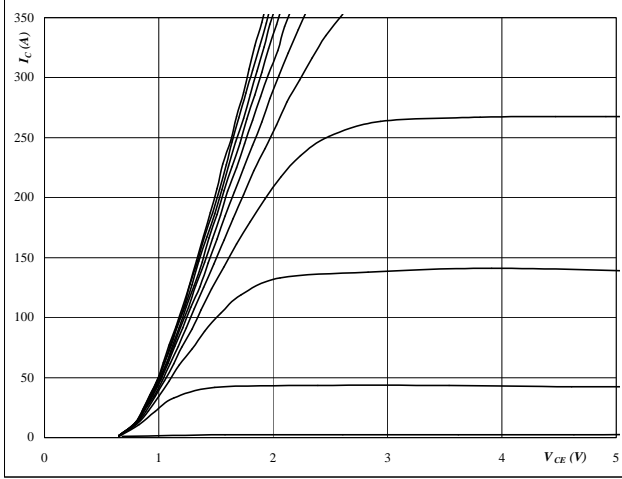


Boost

Figure 1 IGBT

Typical output characteristics

$I_C = f(V_{CE})$

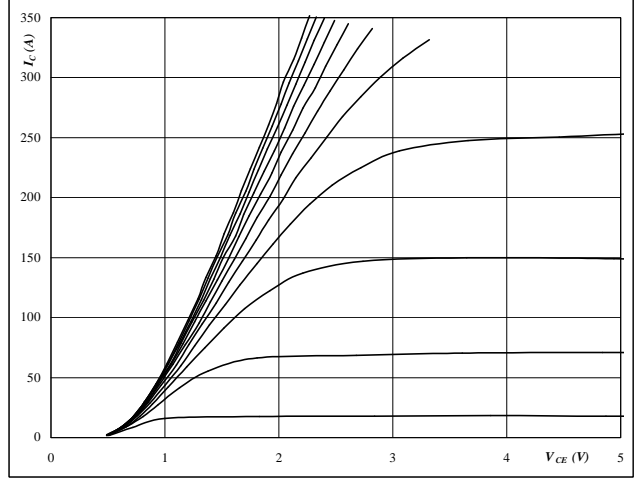


At
 $t_p = 250 \mu s$
 $T_j = 25 \text{ }^\circ C$
 V_{GE} from 7 V to 17 V in steps of 1 V

Figure 2 IGBT

Typical output characteristics

$I_C = f(V_{CE})$

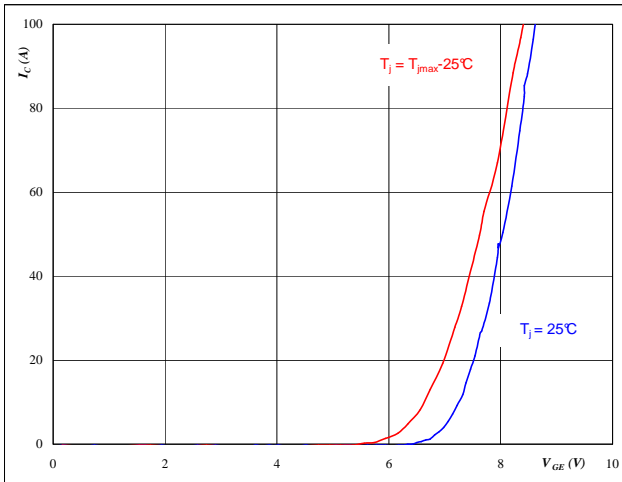


At
 $t_p = 250 \mu s$
 $T_j = 125 \text{ }^\circ C$
 V_{GE} from 7 V to 17 V in steps of 1 V

Figure 3 IGBT

Typical transfer characteristics

$I_C = f(V_{GE})$

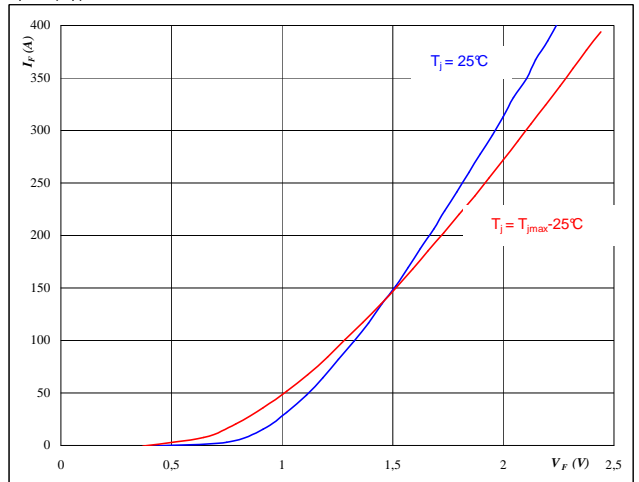


At
 $t_p = 250 \mu s$
 $V_{CE} = 10 V$

Figure 4 Diode

Typical diode forward current as a function of forward voltage

$I_F = f(V_F)$



At
 $t_p = 250 \mu s$

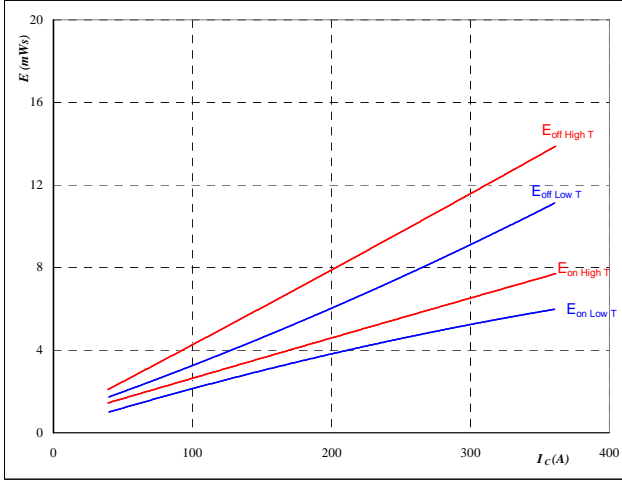


Boost

Figure 5 IGBT

Typical switching energy losses
as a function of collector current

$E = f(I_C)$



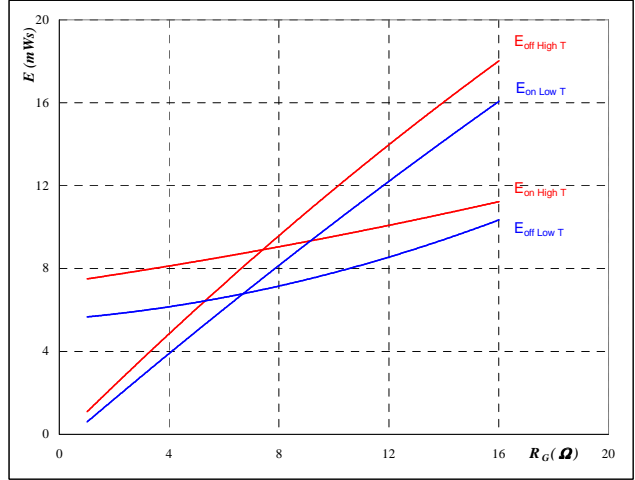
With an inductive load at

- $T_J = 25/125 \text{ } ^\circ\text{C}$
- $V_{CE} = 350 \text{ V}$
- $V_{GE} = \pm 15 \text{ V}$
- $R_{gon} = 4 \text{ } \Omega$
- $R_{goff} = 4 \text{ } \Omega$

Figure 6 IGBT

Typical switching energy losses
as a function of gate resistor

$E = f(R_G)$



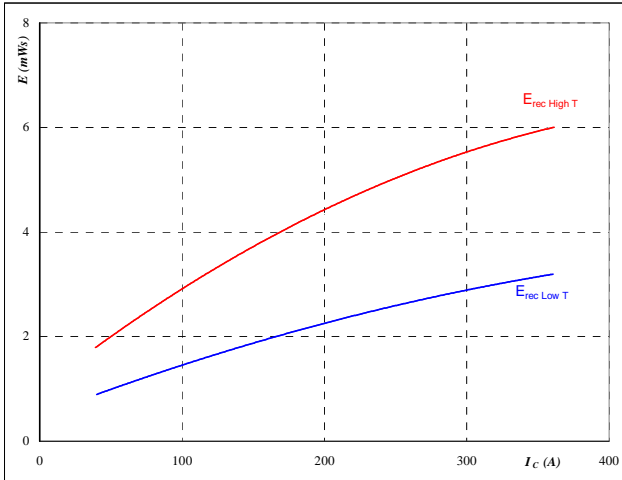
With an inductive load at

- $T_J = 25/125 \text{ } ^\circ\text{C}$
- $V_{CE} = 350 \text{ V}$
- $V_{GE} = \pm 15 \text{ V}$
- $I_C = 200 \text{ A}$

Figure 7 IGBT

Typical reverse recovery energy loss
as a function of collector current

$E_{rec} = f(I_C)$



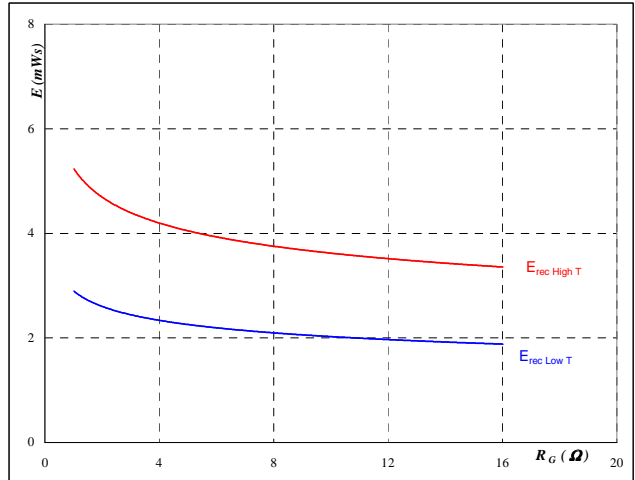
With an inductive load at

- $T_J = 25/125 \text{ } ^\circ\text{C}$
- $V_{CE} = 350 \text{ V}$
- $V_{GE} = \pm 15 \text{ V}$
- $R_{gon} = 4 \text{ } \Omega$

Figure 8 IGBT

Typical reverse recovery energy loss
as a function of gate resistor

$E_{rec} = f(R_G)$



With an inductive load at

- $T_J = 25/125 \text{ } ^\circ\text{C}$
- $V_{CE} = 350 \text{ V}$
- $V_{GE} = \pm 15 \text{ V}$
- $I_C = 200 \text{ A}$

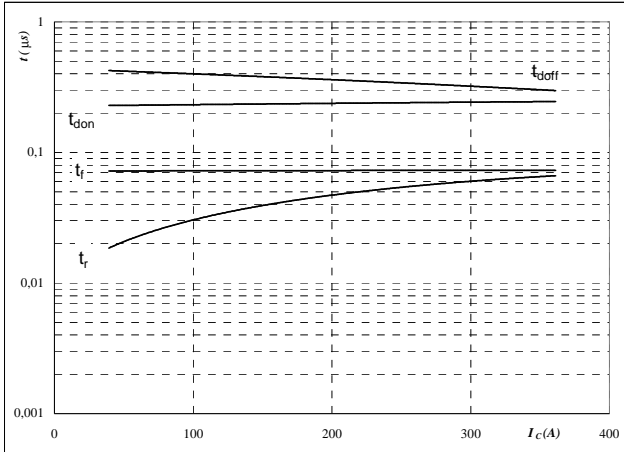


Boost

Figure 9 IGBT

Typical switching times as a function of collector current

$t = f(I_c)$



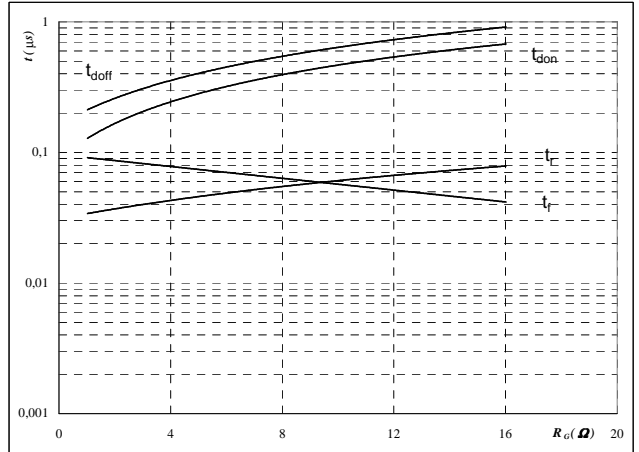
With an inductive load at

$T_j =$	125	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$R_{gon} =$	4	Ω
$R_{goff} =$	4	Ω

Figure 10 IGBT

Typical switching times as a function of gate resistor

$t = f(R_G)$



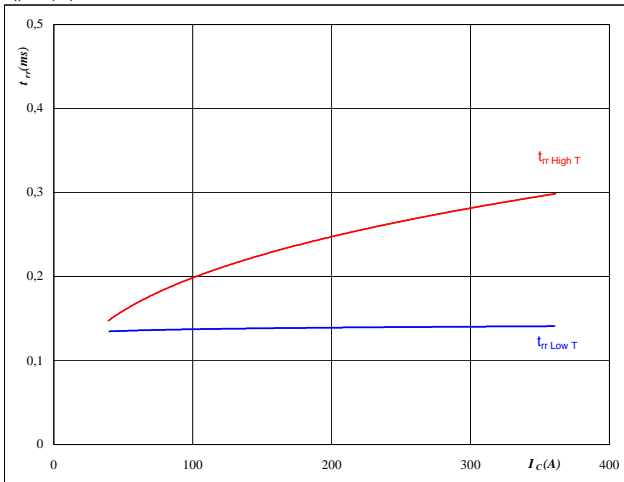
With an inductive load at

$T_j =$	125	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$I_c =$	200	A

Figure 11 Diode

Typical reverse recovery time as a function of collector current

$t_{rr} = f(I_c)$



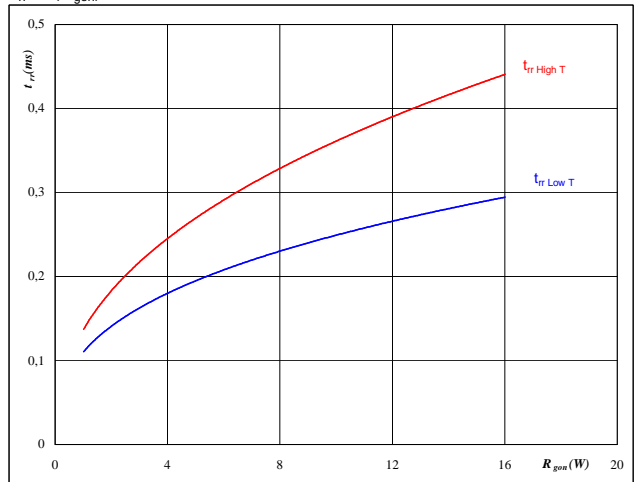
At

$T_j =$	25/125	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$R_{gon} =$	4	Ω

Figure 12 Diode

Typical reverse recovery time as a function of IGBT turn on gate resistor

$t_{rr} = f(R_{gon})$



At

$T_j =$	25/125	°C
$V_R =$	350	V
$I_F =$	200	A
$V_{GE} =$	±15	V

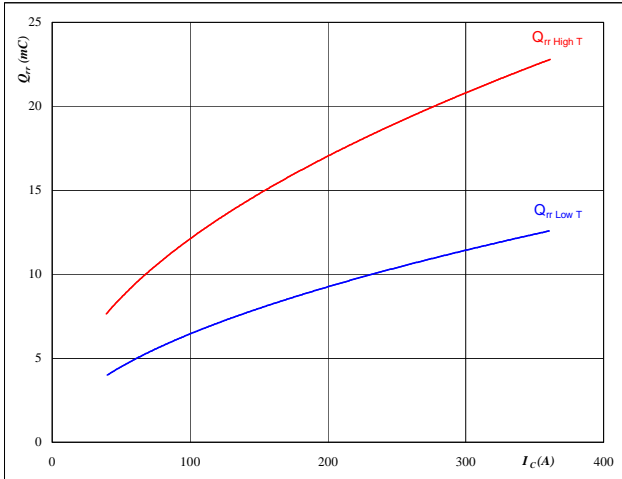


Boost

Figure 13 Diode

Typical reverse recovery charge as a function of collector current

$Q_{rr} = f(I_C)$

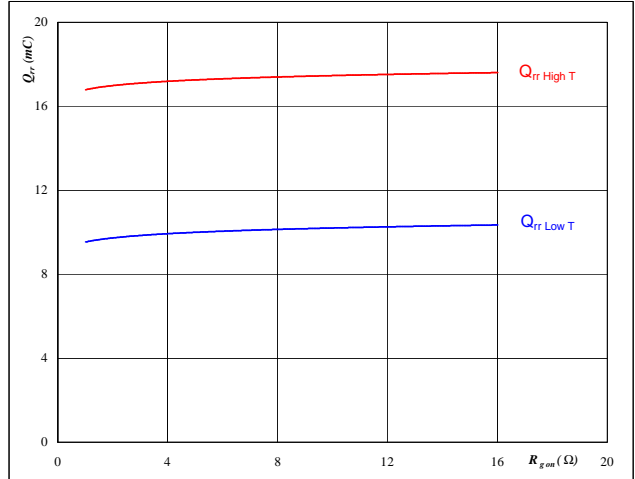


At
 $T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = \pm 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$

Figure 14 Diode

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$Q_{rr} = f(R_{gon})$

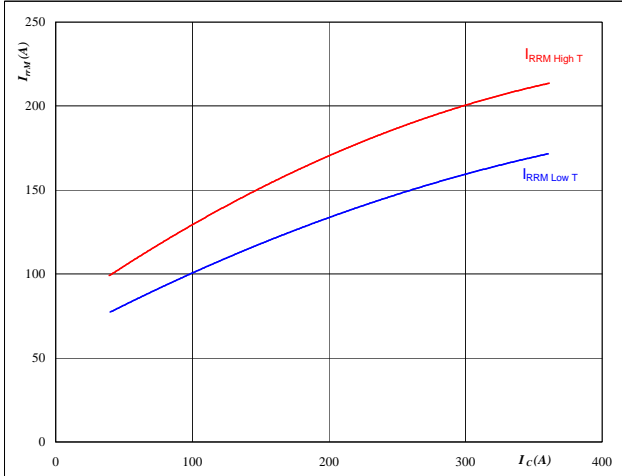


At
 $T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_R = 350 \text{ V}$
 $I_F = 200 \text{ A}$
 $V_{GE} = \pm 15 \text{ V}$

Figure 15 Diode

Typical reverse recovery current as a function of collector current

$I_{RRM} = f(I_C)$

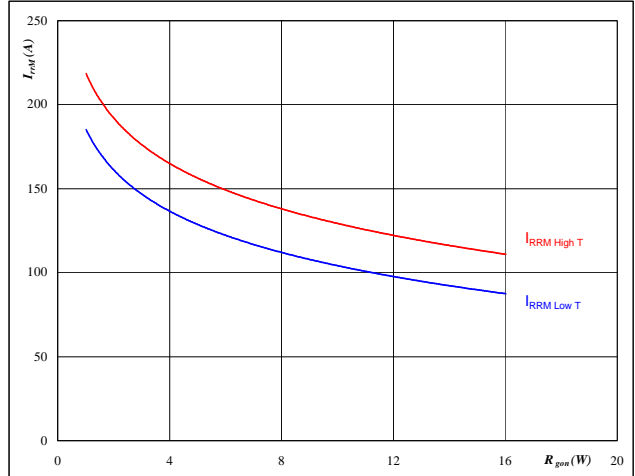


At
 $T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = \pm 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$

Figure 16 Diode

Typical reverse recovery current as a function of IGBT turn on gate resistor

$I_{RRM} = f(R_{gon})$



At
 $T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_R = 350 \text{ V}$
 $I_F = 200 \text{ A}$
 $V_{GE} = \pm 15 \text{ V}$

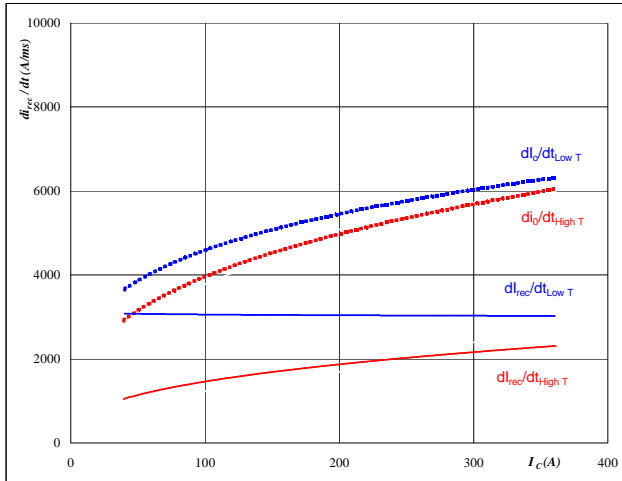


Boost

Figure 17 Diode

Typical rate of fall of forward and reverse recovery current as a function of collector current

$dI_f/dt, dI_{rec}/dt = f(I_c)$

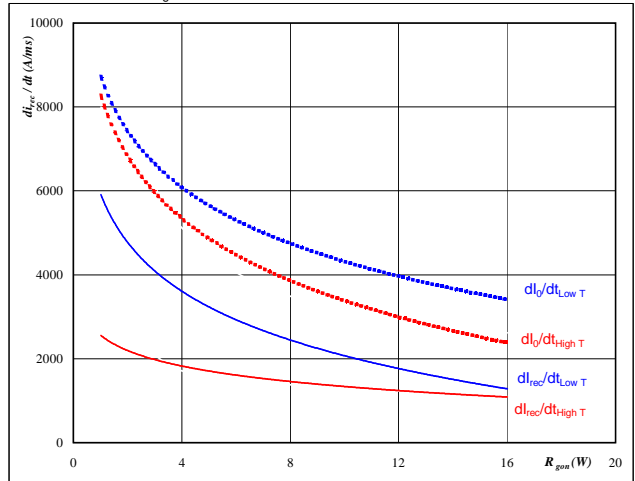


At
 $T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = \pm 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$

Figure 18 Diode

Typical rate of fall of forward and reverse recovery current as a function of IGBT turn on gate resistor

$dI_f/dt, dI_{rec}/dt = f(R_{gon})$

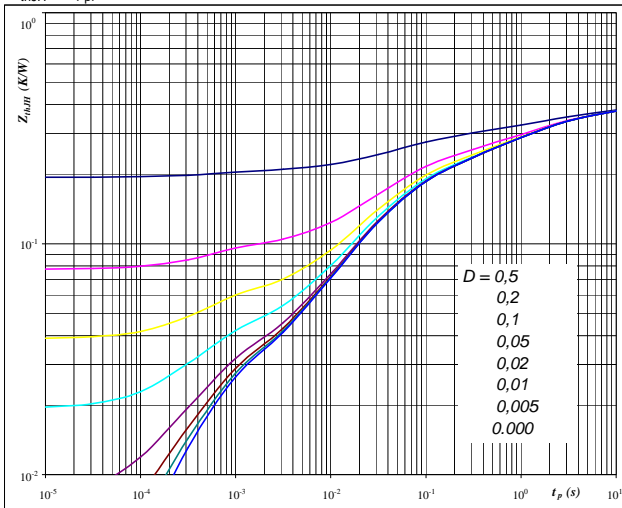


At
 $T_j = 25/125 \text{ } ^\circ\text{C}$
 $V_R = 350 \text{ V}$
 $I_F = 200 \text{ A}$
 $V_{GE} = \pm 15 \text{ V}$

Figure 19 IGBT

IGBT transient thermal impedance as a function of pulse width

$Z_{thJH} = f(t_p)$



At
 $D = t_p / T$
 $R_{thJH} = 0,39 \text{ K/W}$

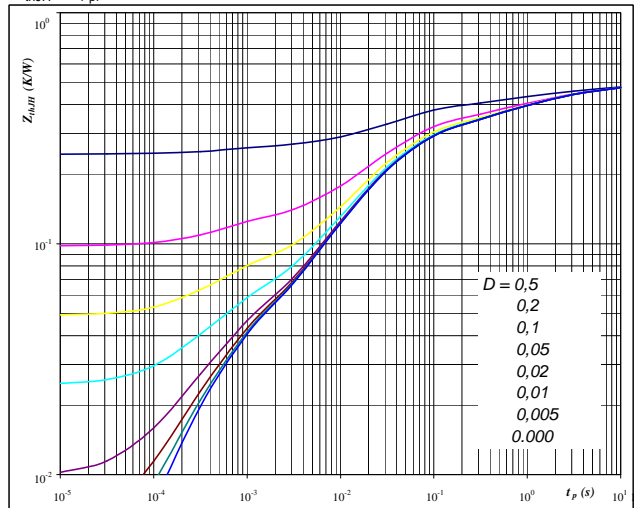
IGBT thermal model values

R (C/W)	Tau (s)
0,02	1,2E+01
0,10	2,6E+00
0,07	4,8E-01
0,11	5,9E-02
0,05	1,3E-02
0,02	4,9E-04

Figure 20 Diode

Diode transient thermal impedance as a function of pulse width

$Z_{thJH} = f(t_p)$



At
 $D = t_p / T$
 $R_{thJH} = 0,49 \text{ K/W}$

Diode thermal model values

R (C/W)	Tau (s)
0,04	9,5E+00
0,09	1,8E+00
0,08	2,9E-01
0,18	3,6E-02
0,06	8,5E-03
0,03	4,7E-04

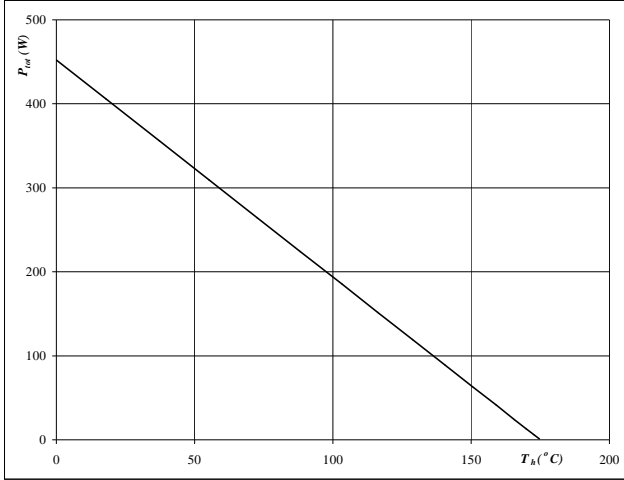


Boost

Figure 21 IGBT

Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_h)$$

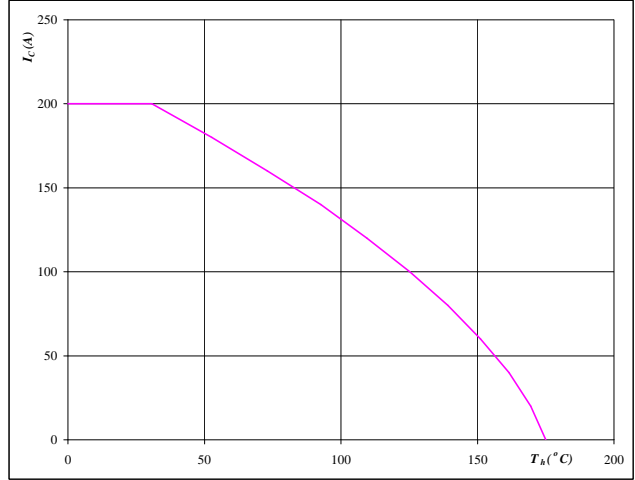


At
T_j = 175 °C

Figure 22 IGBT

Collector current as a function of heatsink temperature

$$I_C = f(T_h)$$

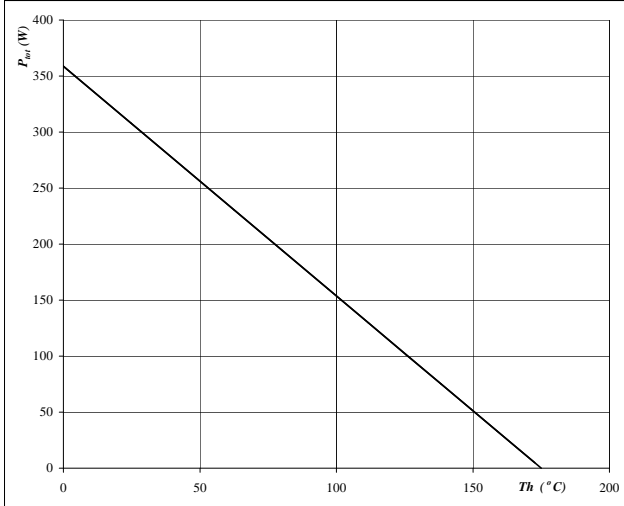


At
T_j = 175 °C
V_{GE} = 15 V

Figure 23 Diode

Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_h)$$

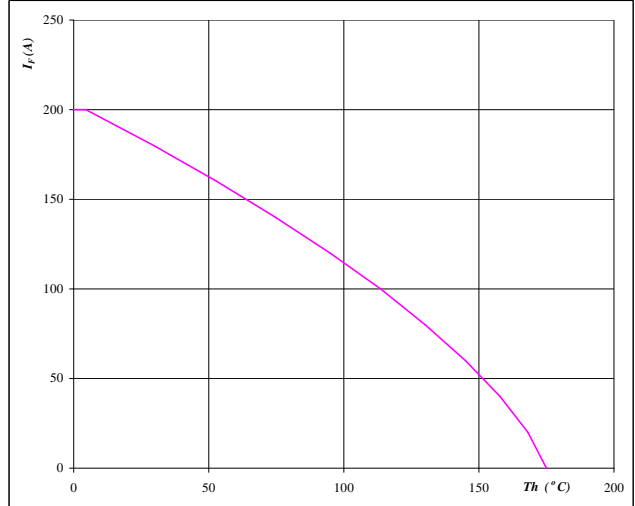


At
T_j = 175 °C

Figure 24 Diode

Forward current as a function of heatsink temperature

$$I_F = f(T_h)$$



At
T_j = 175 °C

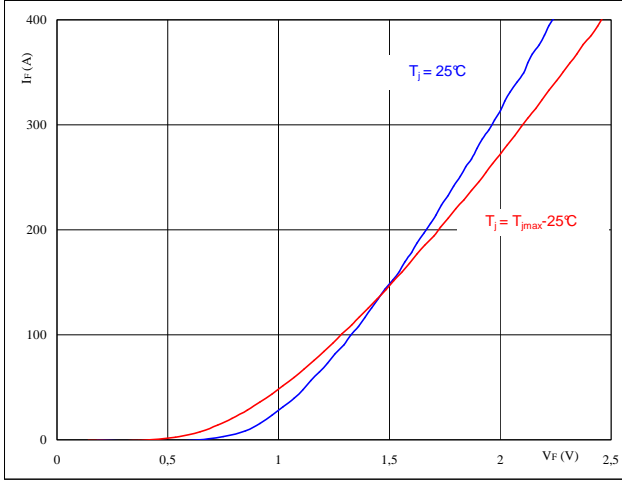


Boost

Figure 25 Boost Inverse Diode

Typical diode forward current as a function of forward voltage

$I_F = f(V_F)$

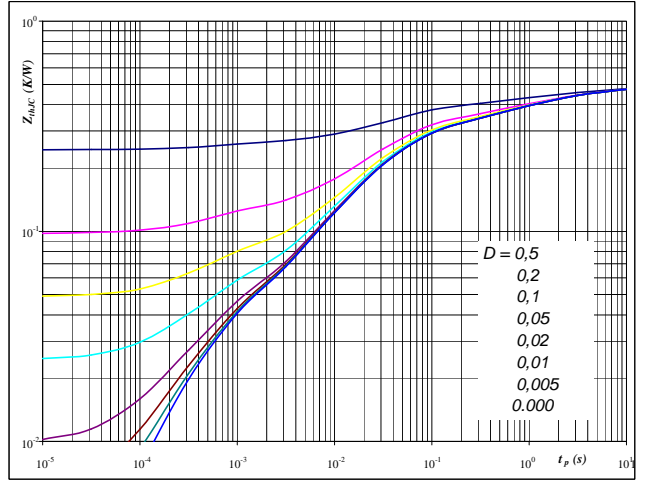


At
 $t_p = 250 \mu\text{s}$

Figure 26 Boost Inverse Diode

Diode transient thermal impedance as a function of pulse width

$Z_{thJH} = f(t_p)$

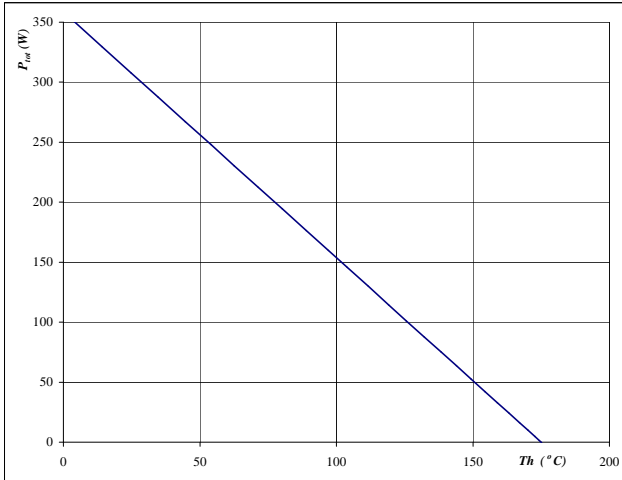


At
 $D = t_p / T$
 $R_{thJH} = 0,49 \text{ K/W}$

Figure 27 Boost Inverse Diode

Power dissipation as a function of heatsink temperature

$P_{tot} = f(T_h)$

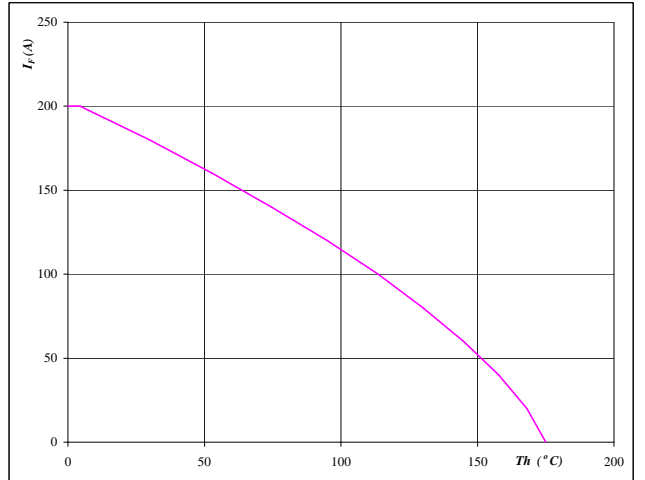


At
 $T_j = 175 \text{ }^\circ\text{C}$

Figure 28 Boost Inverse Diode

Forward current as a function of heatsink temperature

$I_F = f(T_h)$



At
 $T_j = 175 \text{ }^\circ\text{C}$

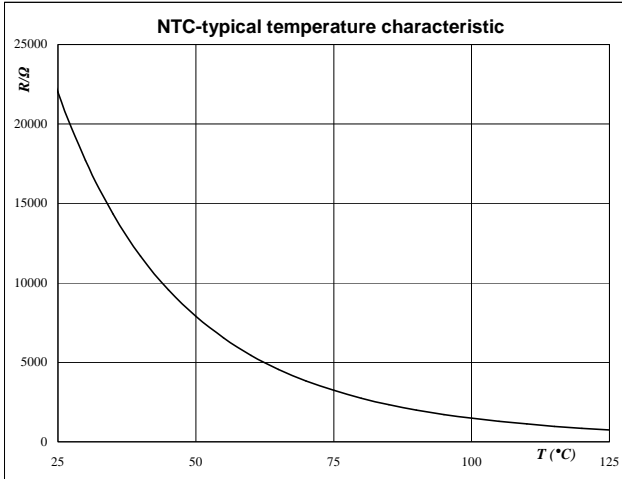


Thermistor

Figure 1 Thermistor

Typical NTC characteristic
as a function of temperature

$$R_T = f(T)$$



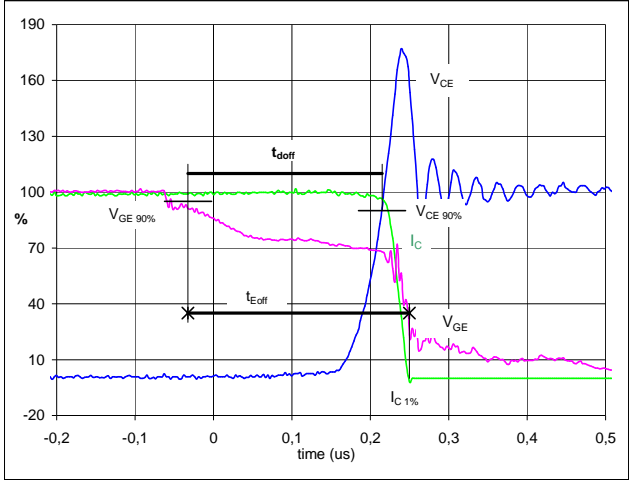


Switching Definitions BUCK MOSFET

General conditions	
T_j	= 125 °C
R_{gon}	= 4 Ω
R_{goff}	= 4 Ω

Figure 1 Output inverter IGBT

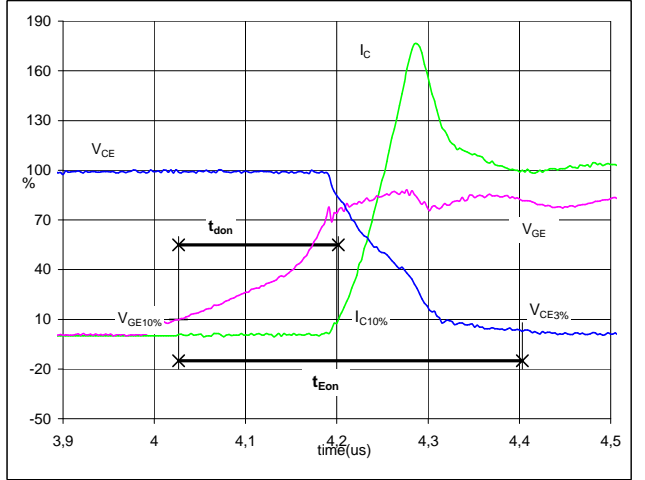
Turn-off Switching Waveforms & definition of t_{doff} , t_{Eoff}
(t_{Eoff} = integrating time for E_{off})



$V_{GE}(0\%) =$	-15	V
$V_{GE}(100\%) =$	15	V
$V_C(100\%) =$	350	V
$I_C(100\%) =$	200	A
$t_{doff} =$	0,27	μs
$t_{Eoff} =$	0,28	μs

Figure 2 Output inverter IGBT

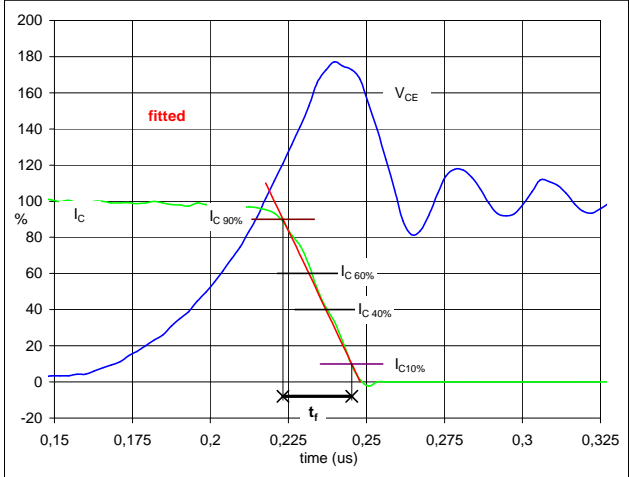
Turn-on Switching Waveforms & definition of t_{don} , t_{Eon}
(t_{Eon} = integrating time for E_{on})



$V_{GE}(0\%) =$	-15	V
$V_{GE}(100\%) =$	15	V
$V_C(100\%) =$	350	V
$I_C(100\%) =$	200	A
$t_{don} =$	0,20	μs
$t_{Eon} =$	0,38	μs

Figure 3 Output inverter IGBT

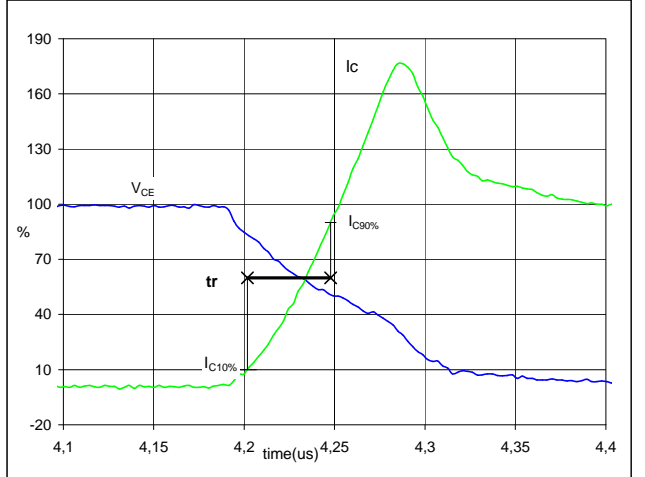
Turn-off Switching Waveforms & definition of t_f



$V_C(100\%) =$	350	V
$I_C(100\%) =$	200	A
$t_f =$	0,02	μs

Figure 4 Output inverter IGBT

Turn-on Switching Waveforms & definition of t_r

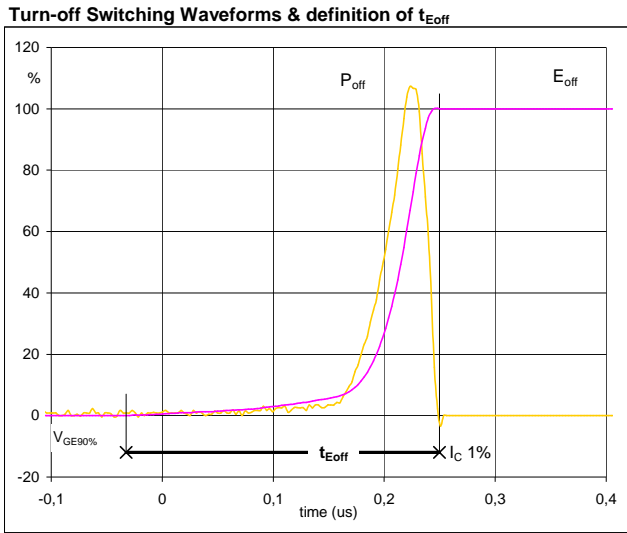


$V_C(100\%) =$	350	V
$I_C(100\%) =$	200	A
$t_r =$	0,05	μs



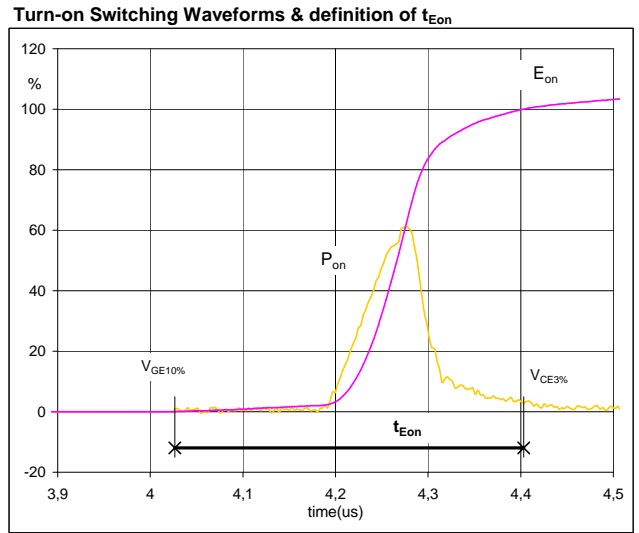
Switching Definitions BUCK MOSFET

Figure 5 Output inverter IGBT



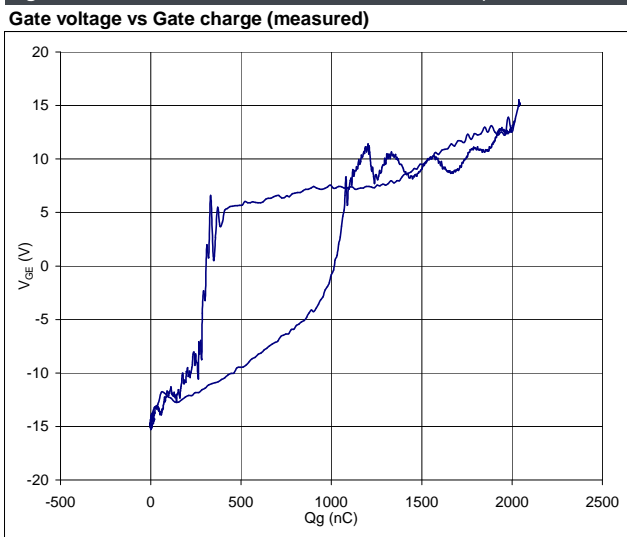
$P_{off} (100\%) = 69,97 \text{ kW}$
 $E_{off} (100\%) = 3,38 \text{ mJ}$
 $t_{Eoff} = 0,28 \text{ } \mu\text{s}$

Figure 6 Output inverter IGBT



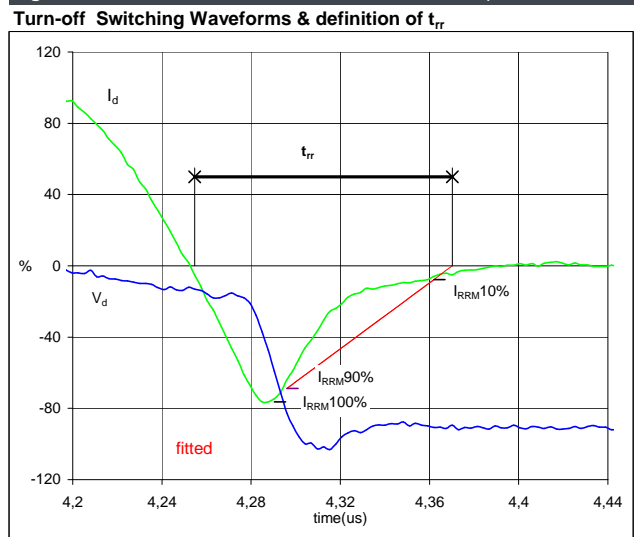
$P_{on} (100\%) = 69,97 \text{ kW}$
 $E_{on} (100\%) = 3,48 \text{ mJ}$
 $t_{Eon} = 0,38 \text{ } \mu\text{s}$

Figure 7 Output inverter IGBT



$V_{GEoff} = -15 \text{ V}$
 $V_{GEon} = 15 \text{ V}$
 $V_C (100\%) = 350 \text{ V}$
 $I_C (100\%) = 200 \text{ A}$
 $Q_g = 2037,49 \text{ nC}$

Figure 8 Output inverter IGBT



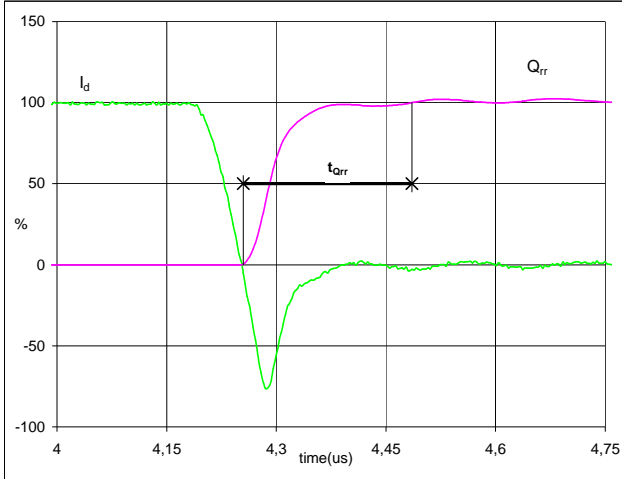
$V_d (100\%) = 350 \text{ V}$
 $I_d (100\%) = 200 \text{ A}$
 $I_{RRM} (100\%) = -154 \text{ A}$
 $t_{rr} = 0,11 \text{ } \mu\text{s}$



Switching Definitions BUCK MOSFET

Figure 9 Output inverter FWD

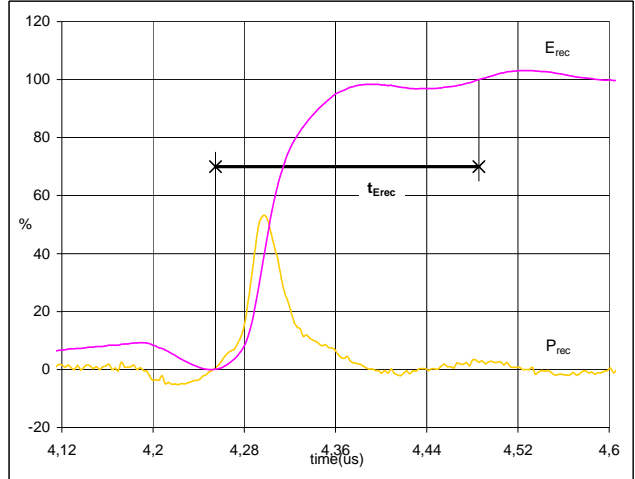
Turn-on Switching Waveforms & definition of t_{Qrr}
(t_{Qrr} = integrating time for Q_{rr})



I_d (100%) =	200	A
Q_{rr} (100%) =	7,28	μC
t_{Qrr} =	0,23	μs

Figure 10 Output inverter FWD

Turn-on Switching Waveforms & definition of t_{Erec}
(t_{Erec} = integrating time for E_{rec})



P_{rec} (100%) =	69,97	kW
E_{rec} (100%) =	1,54	mJ
t_{Erec} =	0,23	μs

Measurement circuits

Figure 11

BUCK stage switching measurement circuit

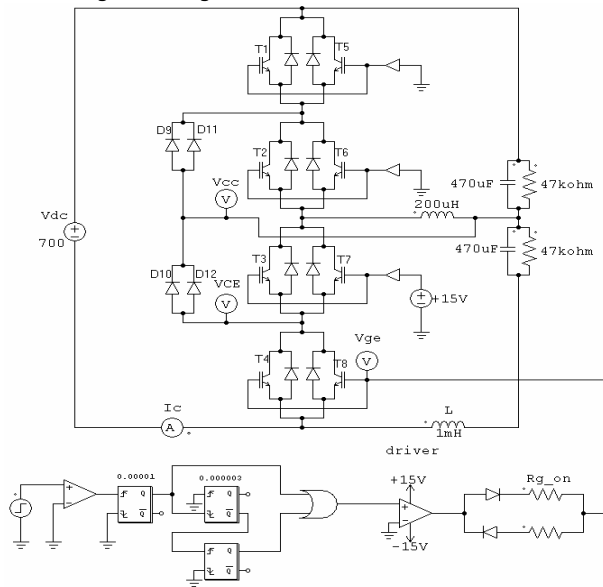
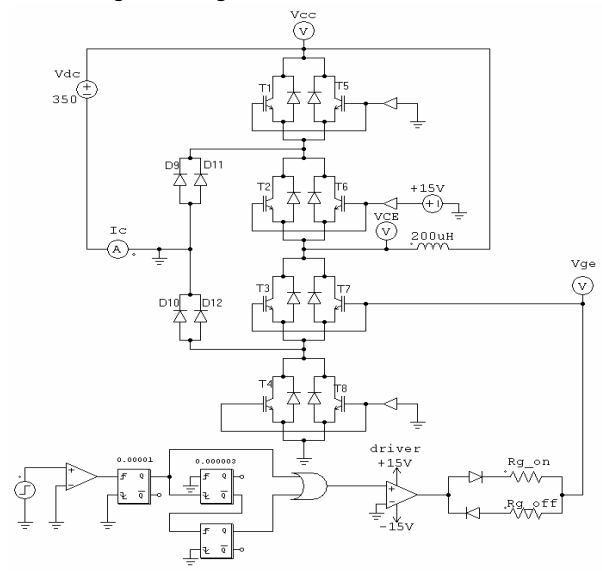


Figure 12

BOOST stage switching measurement circuit





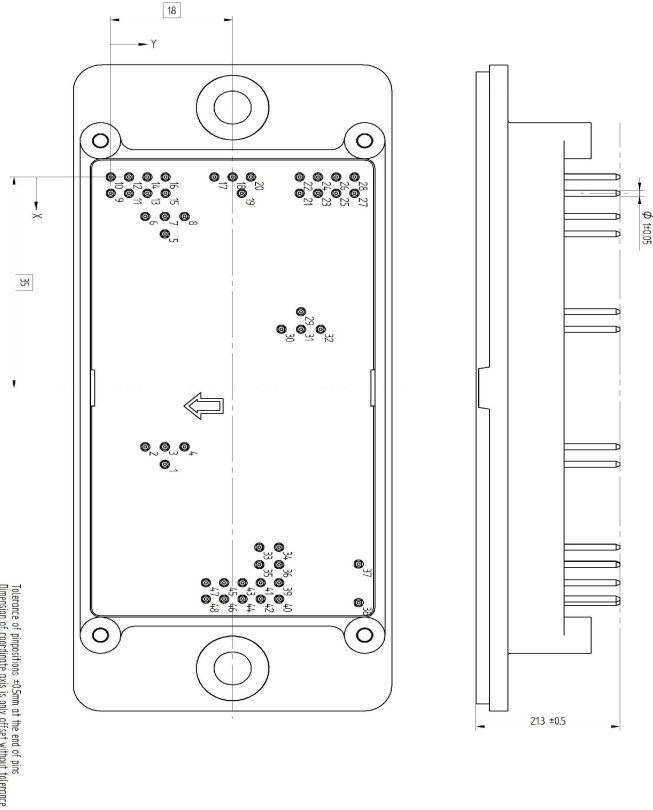
Ordering Code and Marking - Outline - Pinout

Ordering Code & Marking

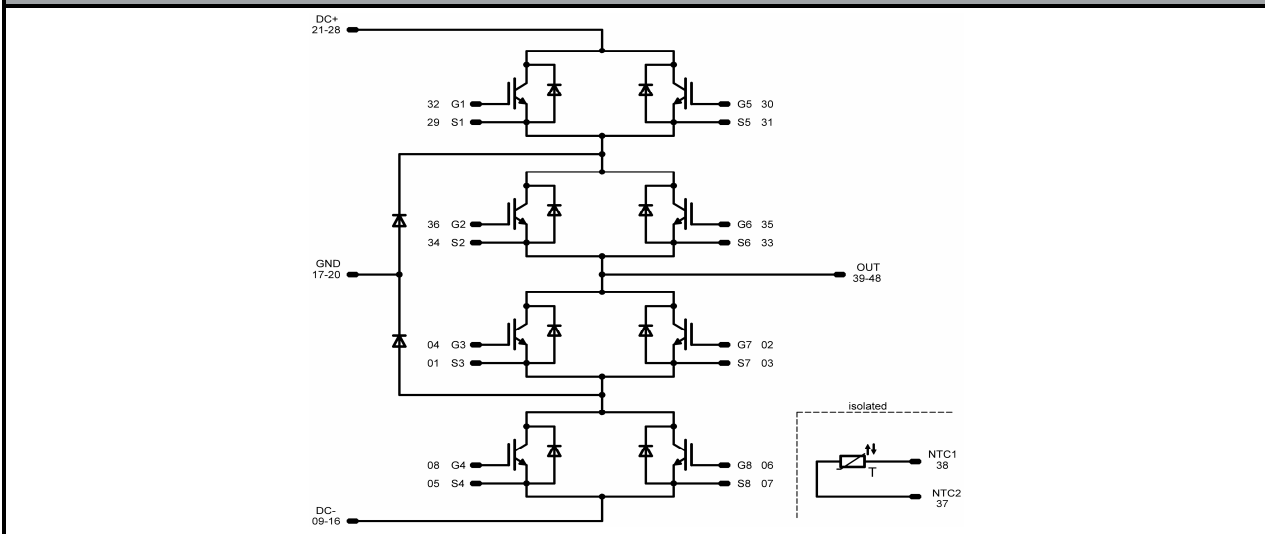
Version	Ordering Code	in DataMatrix as	in packaging barcode as
Standard in flow2 housing	30-F206NIA200SG-M105F25	M105F25	M105F25

Outline

Pin table				Pin table			
Pin	Note 1	X	Y	Pin	Note 1	X	Y
1	S3	47,65	8	25	DC+	2,7	33,3
2	G7	44,75	5,1	26	DC+	0	33,3
3	S7	44,75	8	27	DC+	2,7	36
4	G3	44,75	10,9	28	DC+	0	36
5	S4	9,45	8	29	S1	22,35	28,1
6	G8	6,55	5,1	30	G5	25,25	25,2
7	S8	6,55	8	31	S5	25,25	28,1
8	G4	6,55	10,9	32	G1	25,25	31
9	DC-	2,7	0	33	S6	61,4	21,95
10	DC-	0	0	34	S2	61,4	24,85
11	DC-	2,7	2,7	35	G6	64,3	21,95
12	DC-	0	2,7	36	G2	64,3	24,85
13	DC-	2,7	5,4	37	NTC2	64,2	36,6
14	DC-	0	5,4	38	NTC1	70,6	36,6
15	DC-	2,7	8,1	39	OUT	67,3	24,85
16	DC-	0	8,1	40	OUT	70	24,85
17	GND	0	15,3	41	OUT	67,3	22,15
18	GND	0	18	42	OUT	70	22,15
19	GND	2,7	19,35	43	OUT	67,3	19,45
20	GND	0	20,7	44	OUT	70	19,45
21	DC+	2,7	27,9	45	OUT	67,3	16,75
22	DC+	0	27,9	46	OUT	70	16,75
23	DC+	2,7	30,6	47	OUT	67,3	14,05
24	DC+	0	30,6	48	OUT	70	14,05



Pinout



**PRODUCT STATUS DEFINITIONS**

Datasheet Status	Product Status	Definition
Target	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice. The data contained is exclusively intended for technically trained staff.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data may be published at a later date. Vincotech reserves the right to make changes at any time without notice in order to improve design. The data contained is exclusively intended for technically trained staff.
Final	Full Production	This datasheet contains final specifications. Vincotech reserves the right to make changes at any time without notice in order to improve design. The data contained is exclusively intended for technically trained staff.

DISCLAIMER

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Vincotech products are not authorised for use as critical components in life support devices or systems without the express written approval of Vincotech.

As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in labelling can be reasonably expected to result in significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.